

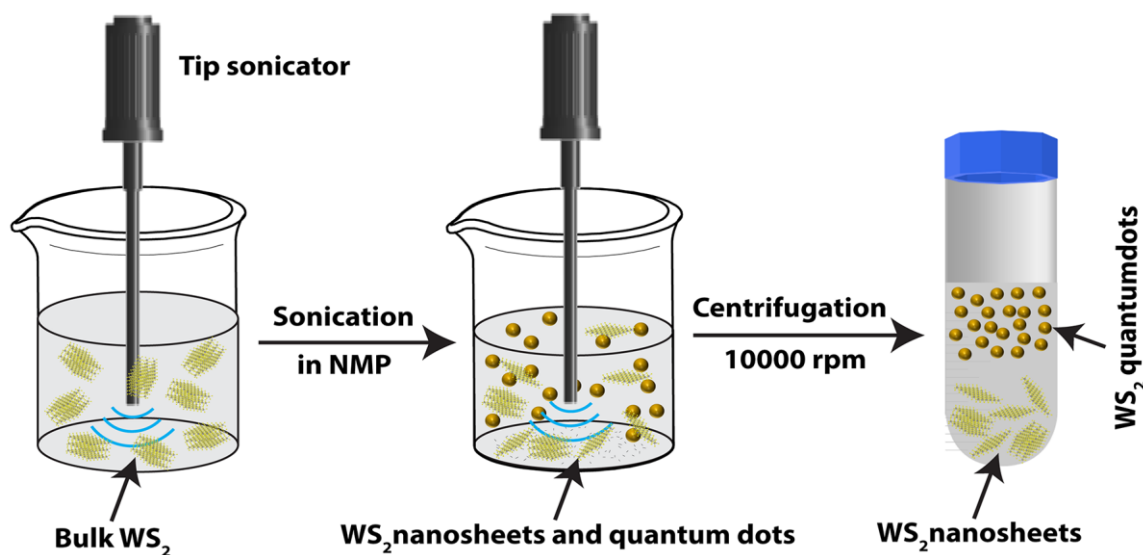
## Supporting Information

### A fully printed ultrafast Si/WS<sub>2</sub> quantum dot photodetector with very high responsivity over the UV to near-infrared region

Subhankar Debnath<sup>1</sup>, Koushik Ghosh<sup>1</sup>, M. Meyyappan<sup>2</sup>, and P. K. Giri<sup>1,2,\*</sup>

<sup>1</sup>Department of Physics, Indian Institute of Technology Guwahati, Guwahati 781039, India

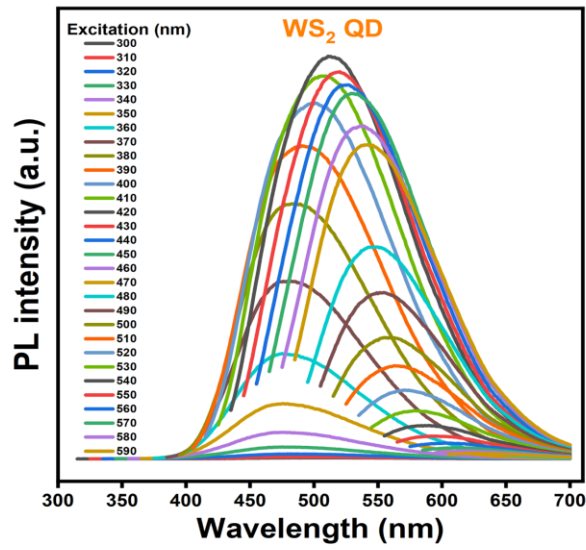
<sup>2</sup>Centre for Nanotechnology, Indian Institute of Technology Guwahati, Guwahati 781039, India



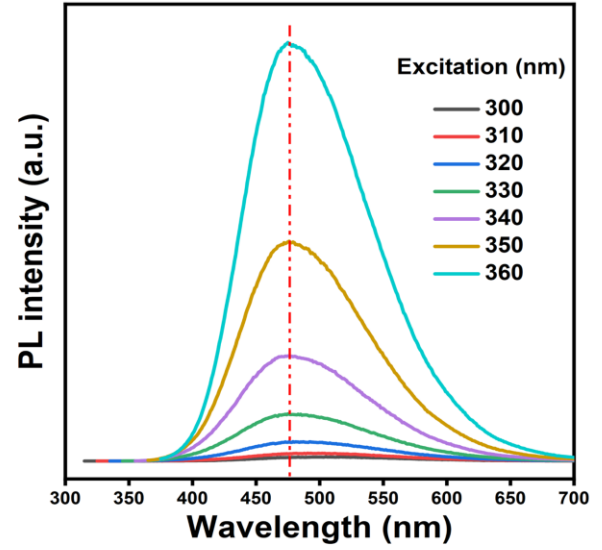
**Figure S1.** Schematic diagram showing the preparation of WS<sub>2</sub> quantum dots.

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\* Corresponding author; email: [giri@iitg.ac.in](mailto:giri@iitg.ac.in)

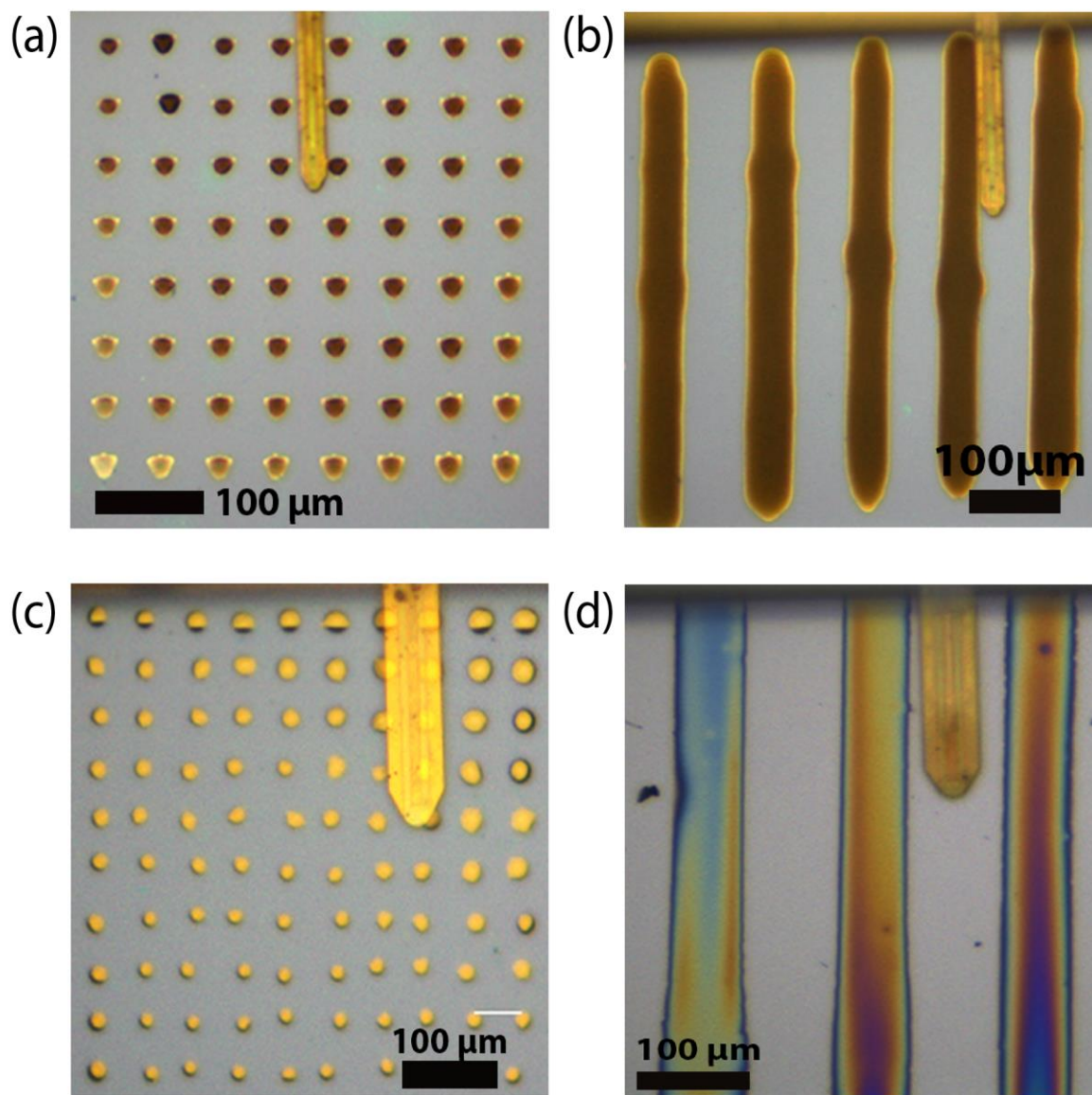


(a)

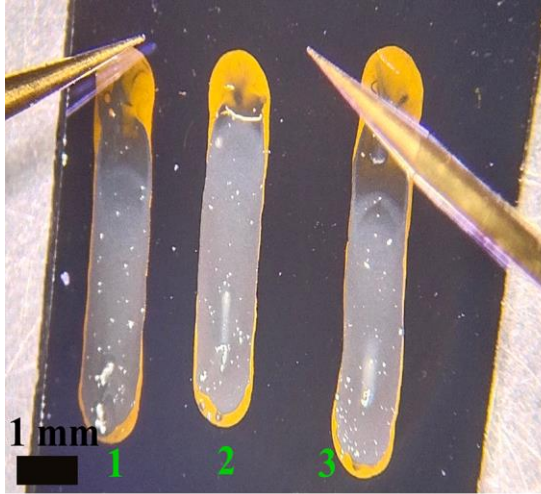


(b)

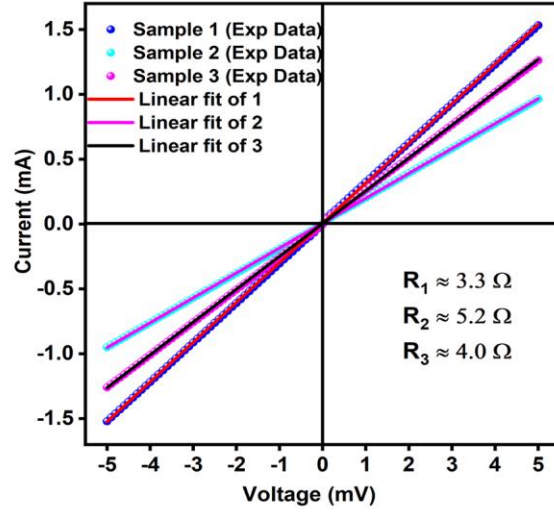
**Figure S2:** (a) PL spectra of WS<sub>2</sub> QDs at different excitation wavelengths. (b) Excitation dependent PL spectra for selective low wavelegths showing no spectral shift.



**Figure S3.** Microscopic image of printed test patterns. (a, b) Printed patterns of Ag NP ink. (c, d) Printed patterns of WS<sub>2</sub> QD ink.



(a)

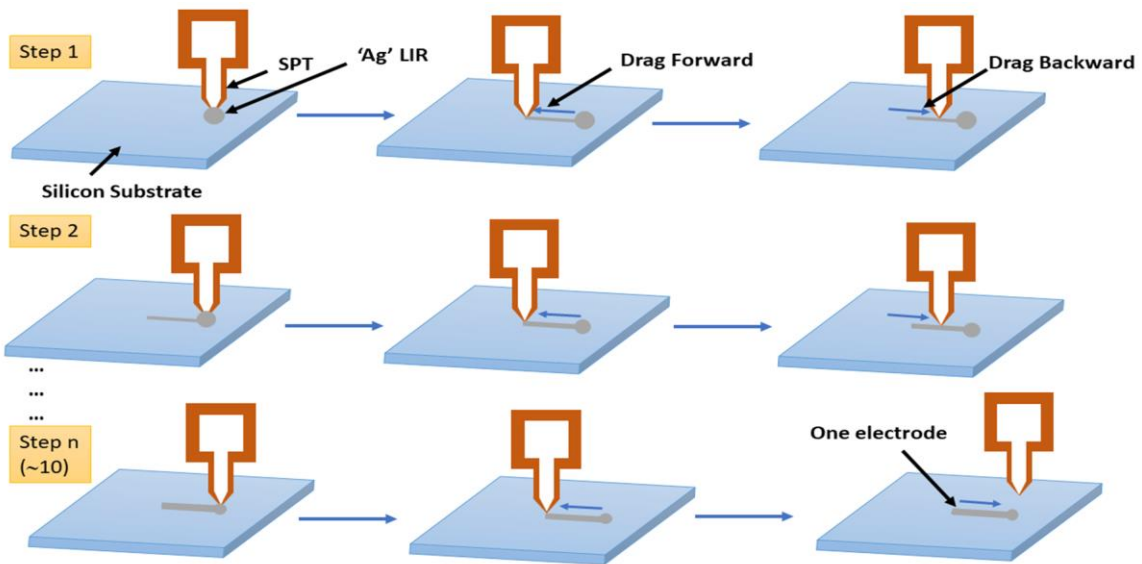


(b)

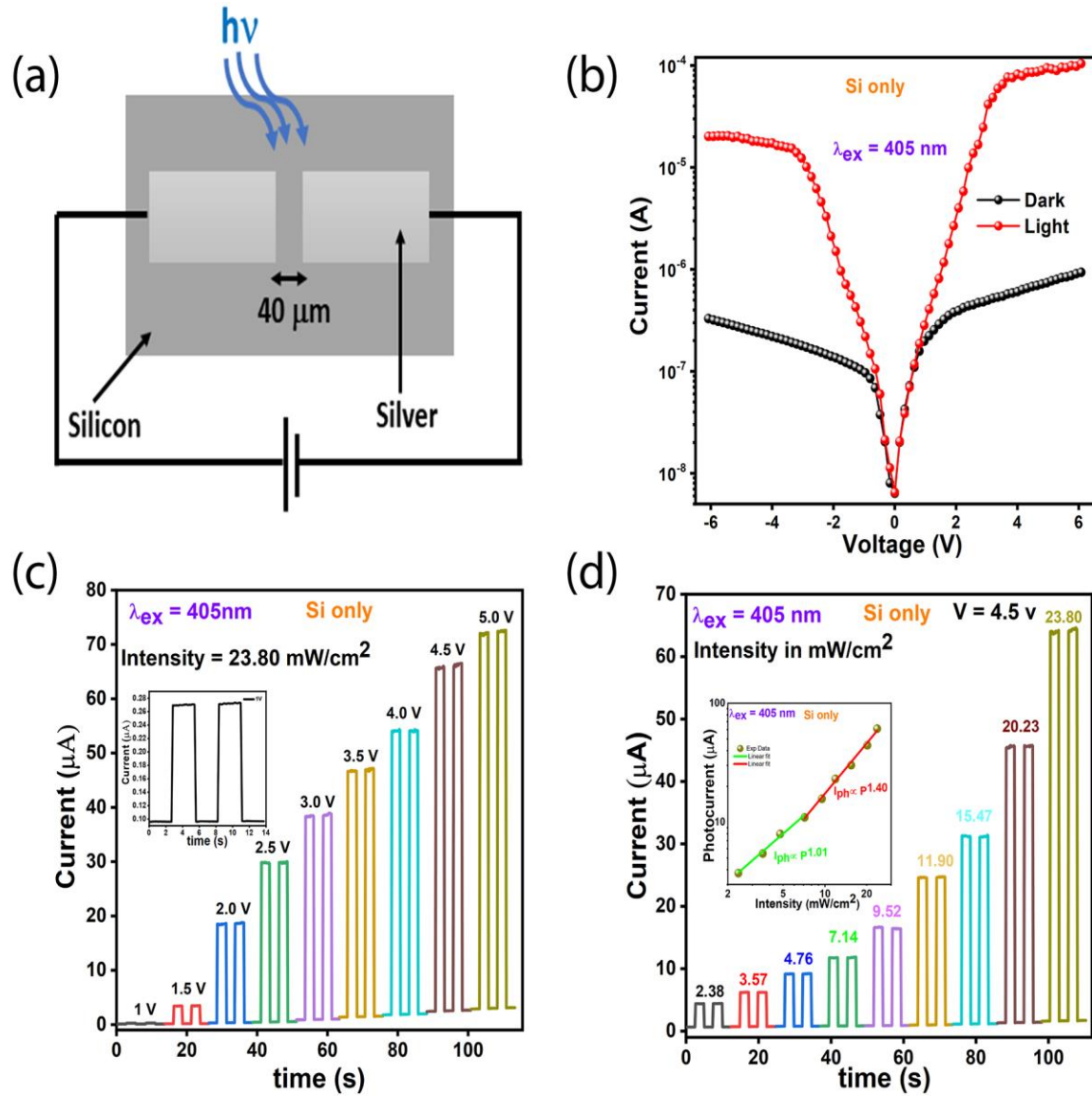
**Figure S4.** (a) Microscopic image of printed silver lines. (b) I-V characteristics of different samples.

**Table S1.** Summary of the resistivity data of the printed silver lines.

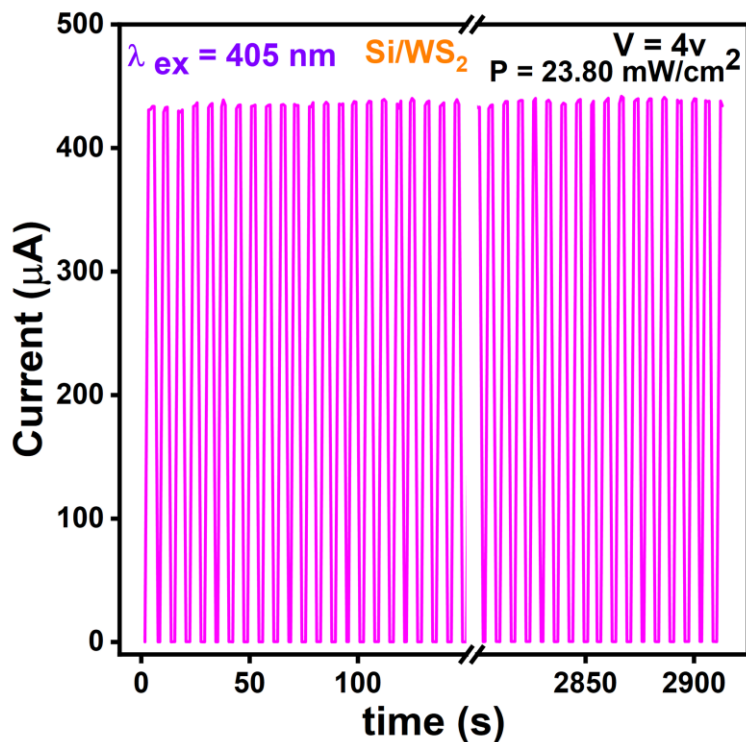
Sample number	Resistance ( $\Omega$ )	Length (mm)	Width ( $\mu\text{m}$ )	Thickness (nm)	Resistivity ( $\Omega\text{-m}$ )
1	3.3	5.95	972	923	$4.98 \times 10^{-7}$
2	5.2	5.71	1002	857	$7.82 \times 10^{-7}$
3	4.0	6.51	970	1066	$6.35 \times 10^{-7}$



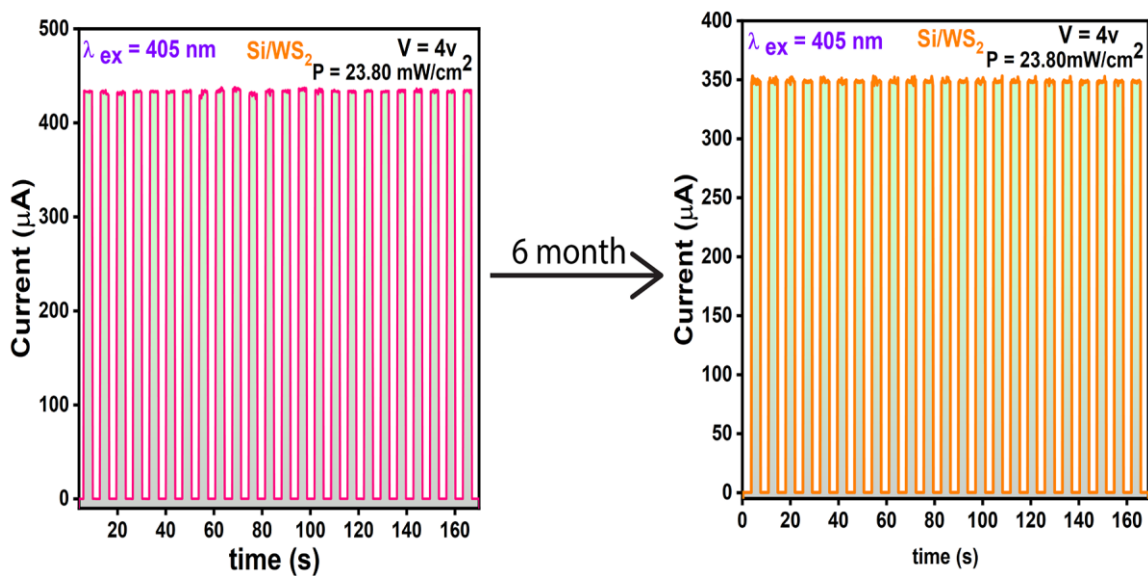
**Figure S5.** Schematic diagram of the device printing process. Step 2 onwards processes are repetitions of step 1.



**Figure S6.** (a) Schematic of the bare Si PD with printed Ag electrodes. (b) I-V characteristics of the PD at dark and under  $405\ \text{nm}$  laser illumination. (c) Voltage-dependent I-t response of the Si PD. (d) Illumination power dependent I-t of the device. The inset shows a light intensity dependent photocurrent showing non-linear response of the device.

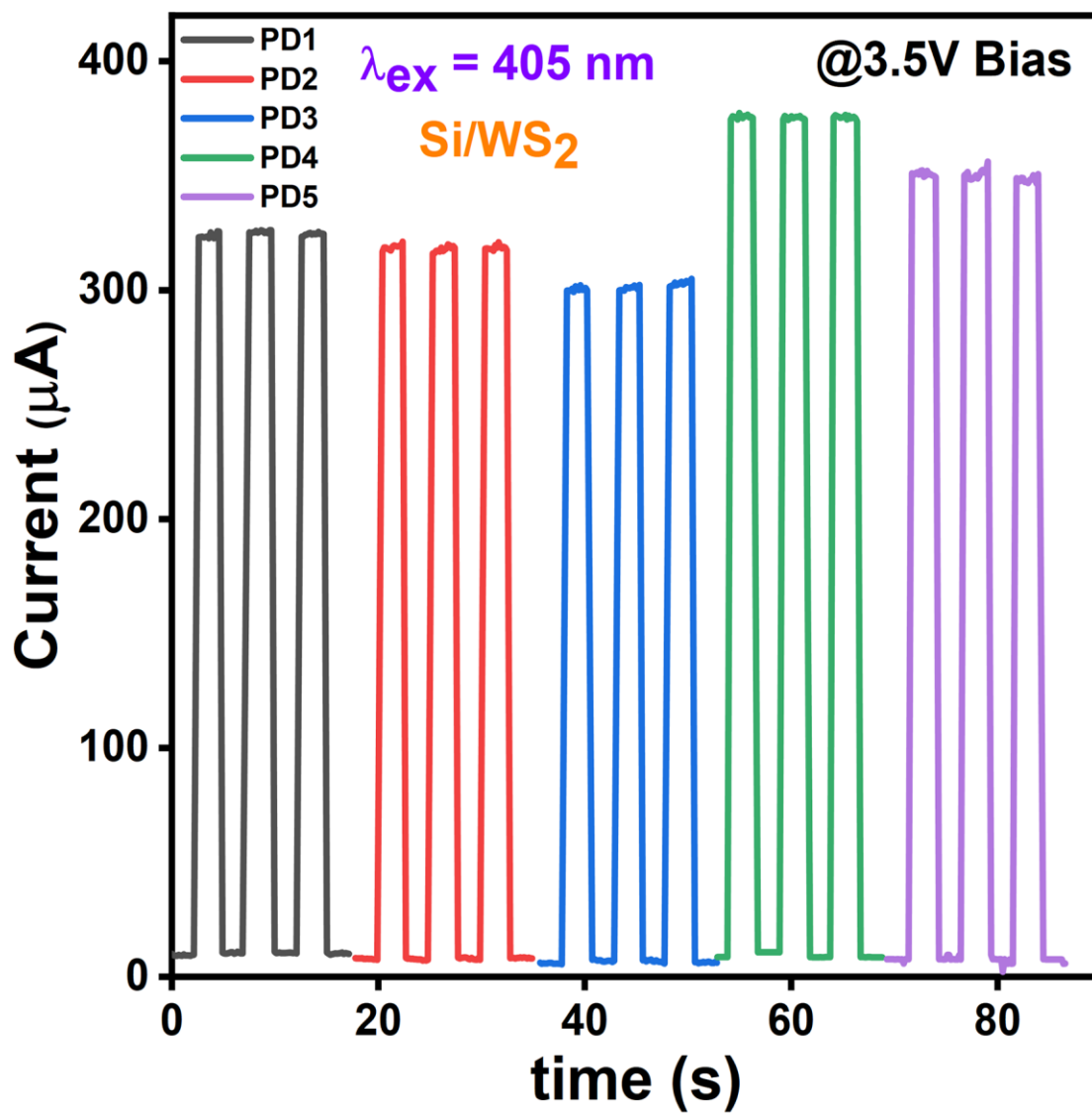


**Figure S7.** Stability of the printed Si/WS<sub>2</sub> photodetector under prolonged light (405 nm) illumination.



**Figure S8.** Storage stability of the printed Si/WS<sub>2</sub> photodetector after six months.





**Figure S9.** Reproducibility of the device fabrication and performance of the PDs. I-t data for five different printed Si/WS<sub>2</sub> PDs show nearly identical results.



**Table S2.** Comparison of the Si/WS<sub>2</sub> photodetector performance fabricated by different techniques.

<b>Synthesis / Fabrication method</b>	<b>I<sub>on</sub> / I<sub>off</sub></b>	<b>Responsivity (A/W)</b>	<b>Specific Detectivity (Jones)</b>	<b>Response Time</b>	<b>Ref.</b>
Sputtering/ silver paste coat	10 <sup>2</sup>	5.70		670 / 998 (μs)	<sup>48</sup>
Li-ion intercalation (dip coat) / Thermal evaporation	10 <sup>3</sup>	1.11	5 × 10 <sup>11</sup>	42 / 72 (ms)	<sup>49</sup>
Thermal decomposition/ photolithography	10 <sup>6</sup>	0.22	1.5 × 10 <sup>12</sup>	16 / 29 (μs)	<sup>50</sup>
Sputtering / Au electrode	1.2 × 10 <sup>3</sup>	5.2	4.8 × 10 <sup>12</sup>	14, <1 (ms)	<sup>51</sup>
Sputtering/thermal evaporation (Drop-cast)	227	186.6	5.4 × 10 <sup>12</sup>	55.1/139.8 (μs)	<sup>24</sup>
Liquid phase exfoliation / Fully printed	5.2 × 10 <sup>3</sup>	126	9.24 × 10 <sup>12</sup>	7.8 / 9.5 (μs)	<i>This work</i>

**Table S3.** Comparison of TMD-based printed photodetector performance.

Materials	Printing Technique	Responsivity (A/W)	Specific Detectivity (Jones)	Response time	Ref.
MoS <sub>2</sub> , graphene electrode	Inkjet printing	0.30	$3.6 \times 10^{10}$	-	<sup>36</sup>
MoS <sub>2</sub> , graphene electrode	Inkjet printing	0.05	$3.18 \times 10^9$	~ 150 (μs)	<sup>37</sup>
MoS <sub>2</sub> , graphene electrode	Aerosol Jet printing	10 <sup>3</sup>	$1.8 \times 10^7$	~ 2, <1 (ms)	<sup>38</sup>
MoS <sub>2</sub> , Ti/ Au electrode	Electrohydrodynamic-Jet Printing / Lithography	3.78	-	-	<sup>39</sup>
WS <sub>2</sub> / graphene electrode	Inkjet/screen printing	$0.61 \times 10^{-3}$	-	-	<sup>40</sup>
Si /WS <sub>2</sub> , Silver electrode	Microcantilever-based printing	126	$9.24 \times 10^{12}$	7.8 / 9.5 (μs)	This work

## REFERENCES

- (48) Lan, C.; Li, C.; Wang, S.; He, T.; Jiao, T.; Wei, D.; Jing, W.; Li, L.; Liu, Y. Zener Tunneling and Photoresponse of a WS<sub>2</sub>/Si van Der Waals Heterojunction. *ACS Appl. Mater. Interfaces* **2016**, *8* (28), 18375–18382. <https://doi.org/10.1021/acsami.6b05109>.
- (49) K. Chowdhury, R.; Maiti, R.; Ghorai, A.; Midya, A.; K. Ray, S. Novel Silicon Compatible P-WS<sub>2</sub> 2D/3D Heterojunction Devices Exhibiting Broadband Photoresponse and Superior Detectivity. *Nanoscale* **2016**, *8* (27), 13429–13436. <https://doi.org/10.1039/C6NR01642A>.
- (50) Wu, E.; Wu, D.; Jia, C.; Wang, Y.; Yuan, H.; Zeng, L.; Xu, T.; Shi, Z.; Tian, Y.; Li, X. In Situ Fabrication of 2D WS<sub>2</sub>/Si Type-II Heterojunction for Self-Powered Broadband Photodetector with Response up to Mid-Infrared. *ACS Photonics* **2019**, *6* (2), 565–572. <https://doi.org/10.1021/acsp Photonics.8b01675>.
- (51) Pal, S.; Mukherjee, S.; Jangir, R.; Nand, M.; Jana, D.; Mandal, S. K.; Bhunia, S.; Mukherjee, C.; Jha, S. N.; Ray, S. K. WS<sub>2</sub> Nanosheet/Si p–n Heterojunction Diodes for UV–Visible Broadband Photodetection. *ACS Appl. Nano Mater.* **2021**, *4* (3), 3241–3251. <https://doi.org/10.1021/acsanm.1c00421>.